

PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER	
NOMINAL FREQUENCY	32.768 KHz
PRODUCT TYPE	TYPE G9 SMD CRYSTAL
SPEC. NO. (P/N)	G93270002
CUSTOMER P/N	
ISSUE DATE	Oct.31,2013
VERSION	C

APPROVED	PREPARED	QA
Brenda	Viklai Lu	Bedrycri
APPROVED BY	APPROVED BY CUSTOMER:	
Please return one copy with approval to PSE-TW		

PSE Technology Corporation

No.2, Tzu-Chiang 5th Rd, Chung Li Industrial Park, Chung Li City, Taoyuan County, Taiwan (R.O.C.)

TEL: 886-3-451-8888 FAX: 886-3-461-3865

http://www.saronix-ecera.com.tw

*Pb-free

*RoHS Compliant

*HF-Halogen Free

*REACH Compliant



*** A company of PERICOM Semiconductor Corporation ***

E0-R-4-014 Rev. E Page i

G93270002

VER. C

31-Oct-13

VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
А	Apr.18,2011			Initial Release	
В	Oct.3,2011			Changed Operating Temperature Range from -30~70°C to -40~85°C & Added Shunt Capacitance 7pF	
С	Oct.31,2013			Revised to RoHS Compliant	
				_	

G93270002

VER. C

31-Oct-13

ELECTRICAL SPECIFICATIONS

SRe Part Number: G93270002

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 20	ppm	at 25°C ± 5°C
Load Capacitance	CL	12.5	pF	Тур.
Drive Level	DL	0.1 / 0.5	μ W	Typ / Max.
Equivalent Series Resistance	ESR	90	ΚΩ	Max.
Temperature Coefficient	K	-0.03	ppm/°C ²	Тур.
Operating Temperature Range	TR	-40~85	°C	
Shunt Capacitance	C0	7	pF	Max.
Storage Temperature Range		-55~125	°C	
Aging		± 3	ppm	Max 1st year
Insulation Resistance		500	ΜΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm
2	Shear test	A static load of 20N(2.04kgf) using a R0.5 scratch tool, shall be applied on the core of the component and in the direction of the arrow and held for 5 seconds.	• Equivalent series resistance(E.S.R) change: Within 5kΩ
3	Core body strength	A static load of 10N(1.02kgf) using a R0.5 pressure rod shall be applied to the center in the direction of the arrow and held for 10 seconds.	
4	Vibration	Endurance conditioning by a frequency sweep shall be made. The entire frequency range, from 10Hz to 55Hz and return to 10Hz, shall be transversed in 1 minute. Amplitude (total excursion): 1.5mm, This motion shall be applied for a period of 2 hours in each of 3 mutually perpendicular axes (a total of 6 hours). For other procedures, refer to JIS C 60068-2-6.	
5	Shock	Peak acceleration: 9810m/s2 · Duration of the pulse: 1ms, Three successive shock shall be applied 3 times perpendicular axes. For other procedures, refer to JIS C 60068-2-27.	

E0-R-4-014 Rev. E Page 1

G93270002

VER. C 31-Oct-13

6	Cold	Quartz crystal units shall be stored in the -40±3°C atmosphere for 1000 hours. Other procedures conform to JIS C 60068-2-1.			 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ
7	Dry heat	Quartz crystal units shall be stored in the 100±2°C atmosphere for 100 hours. Other procedures conform to JIS C 60068-2-2.			After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
8	Damp heat	Quartz crystal units shall be stored in the 40±2℃ atmosphere with 90 to 95% relative humidity for 1000 hours. Other procedures conform to JIS C 60068-2-3.			
9	Change of temperature	Quartz crystal units shall be subjected successively 100 cycles of temperature change shown below. Other procedures conform to JIS C 0025.			100
		1 2 3 4	Temperatur -40±3°C Normal tempera 100±2°C Normal tempera	30min. ture Within 30 sec. 30min.	
10	Sealing	Both the test methods specified below shall be applied. Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes. Quartz crystal units shall be tested by Mass spectrometric leakage detector to measure the leakage			 • Without repetitive leaking bubbles from quartz crystal units. • 1×10-9 Pa·m3/s or less
11	Aging	rate of helium gas. Quartz crystal units shall be stored in the 85±3°C atmosphere for 720±12 hours.			 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
	2 Solder-ability Terminals coated with flux shall be immersed in the solder bath for 3.5±0.5 seconds.		Minimum 95% of immersed terminal shall		
12	Solder-ability	solder bat	n ior 3.5±0.5 sec	onds.	be covered with new uniform solder.
12	Toolder-ability	solder bat	Items	Conditions	be covered with new uniform solder.
12	Colder-ability	solder bat			be covered with new uniform solder.
12	Colder-ability		Items	Conditions	be covered with new uniform solder.

G93270002

Resistance to Reflow soldering method soldering heat 温度プロファイル Temperature profile はんだ付け Soldering 260 Soldering temperature 220 60±10s 徐冷(常温自然放置) 予熱 Slow cooling(Stored Pre-heating at room temperature) 160 Within 5s $90 \pm 10s$ • Frequency change: Within ±5ppm Peak temperature: 260±5°C for within 5seconds. • Equivalent series resistance (E.S.R) Soldering temperature: 220°C or higher for 60±10 change: Within 10kΩ seconds. · After conditioning, quartz crystal units Pre-heating temperature: 160±10°C for 90±10 seconds shall be subjected to standard atmospheric Quartz crystal units which is put on PCB shall be conditions for 1 hour, and measured. through reflow soldering furnace twice with the condition · Without distinct deformation in shown above. appearance. Soldering iron method • Frequency change: Within ±5ppm Terminals shall be applied 400±10℃ soldering iron heat • Equivalent series resistance(E.S.R) for 3.5±0.5 seconds twice. change: Within 5kΩ · After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. · Without distinct deformation in appearance. Solubility to Soak cleaning Without mechanical damage such as breaks and satisfy sealing specification. resistance Quartz crystal units shall be soaked in isopropyl alcohol at normal temperature for 90 • Frequency change: Within ±5ppm seconds. • Equivalent series resistance(E.S.R) change: Within 5kΩ · Without distinct deformation in appearance. · Marking shall be legible.

VER. C

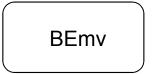
31-Oct-13

G93270002

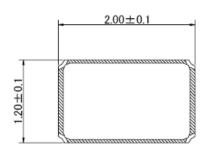
VER. C

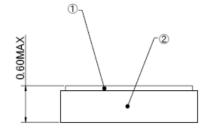
31-Oct-13

Marking

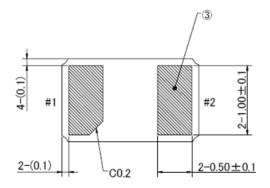


Dimensions (Units: mm)

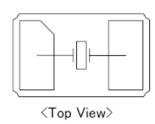




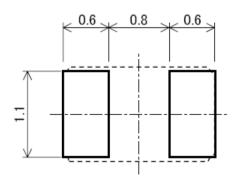




内部接続図 Internal connection



Land dimensions(unit: mm)

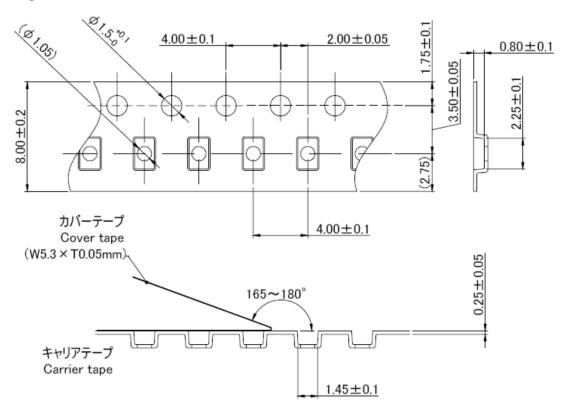


G93270002

VER. C

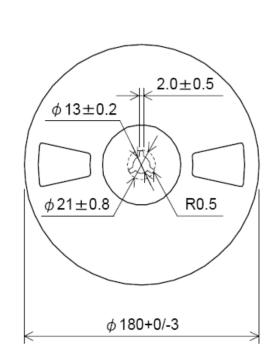
31-Oct-13

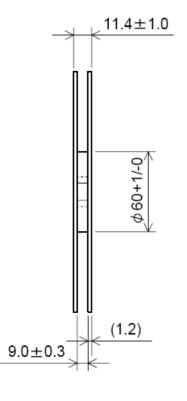
TAPING



REEL

Reel





E0-R-4-014 Rev. E